Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/781,574	HUJANEN ET AL.	
Examiner	Art Unit	
Kevin M. Bernatz	1773	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Google sevel of "otomic layer deposition") "prohite"	10/14/8	Per	